MF1ICS5005

Sawn bumped 120 µm wafer specification on UV tape

Rev. 3.2 — 23 June 2010Product data sheet addendum179132PUBLIC

1. General description

The MF1ICS5005 is a contactless smart card IC designed for card IC coils following the "MIFARE card IC coil design guide" and is qualified to work properly in NXP Semiconductors' reader environment, which is built according to NXP Semiconductors' specification.

This specification describes electrical, physical and dimensional properties of sawn wafers delivered on UV-tape.

2. Ordering information

Table 1. Ordering inform	Ordering information			
Type number	Package			
	Name	Description	Version	
MF1ICS5005W/U7DL	Wafer	Bumped die on sawn wafer	-	

3. Mechanical specification

3.2

3.1 Wafer

Diameter:	200 mm (8")
 Maximum diameter after foil expansion: 	210 mm
Thickness:	120 μm ± 15 μm
Flatness:	not applicable
• PGDW:	27720
Wafer backside	

٠	Material:	Si
٠	Treatment:	ground and stress relieve
•	Roughness:	R _a max. 0.5 μm R _t max. 5 μm



3.3 Chip dimensions

 Chip (step) size: 	1.062 x 1.012 mm
 Scribe lines¹: 	x-line: 48.4 μm
	y-line: 48.4 μm
 Gap between chips: 	typ. 27 μm
	min, 5 um

3.4 Passivation

•	Туре:	sandwich structure
•	Material:	PSG / Nitride
•	Thickness:	500 nm / 600 nm

3.5 Au bump

- Bump hardness:
- Bump shear strength: > 70 MPa
- Bump height: 18 μm
- Bump height uniformity:
 - within a die: $\pm 2 \mu m$
 - within a wafer: $\pm 3 \,\mu m$
 - wafer to wafer: $\pm 4 \ \mu m$
- Bump flatness: $\pm 1.5 \ \mu m$
- Bump size:
- LA, LB, VSS²
 TESTIO²
 Bump size variation:
 ± 5 μm
- Under bump metallization: sputtered TiW

Remark: Substrate is connected to VSS.

3.6 Fail die identification

Electronic wafer mapping covers the electrical test results and additionally the results of mechanical / visual inspection.

35 - 80 HV 0.005

No inkdots are applied.

2. Pads VSS and TESTIO are disconnected when wafer is sawn.

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^{1.} typical scribe line width specified (measured from metal to metal), scribe line may vary due to changing foil expansion

4. Limiting values

Table 2. Limiting values^{[1][2][3]}

In accordance with the Absolute Maximum Rating System (IEC 60134)

Symbol	Parameter	Conditions	Min	Max	Unit
l _{i(max)}	maximum input current		-	30	mA
P _{tot/pack}	total power dissipation per package		-	200	mW
T _{stg}	storage temperature		-55	+125	°C
T _{amb}	ambient temperature		-25	70	°C
l _{lu}	latch-up current		±100	-	mA
V_{ESD}	electrostatic discharge voltage	measured on pin LA-LB	<u>[4]</u>	2	kV

[1] Stresses above one or more of the limiting values may cause permanent damage to the device.

- [2] These are stress ratings only. Operation of the device at these or any other conditions above those given in the Characteristics section of the specification is not implied.
- [3] Exposure to limiting values for extended periods may affect device reliability.
- [4] MIL Standard 883-C method 3015; Human body model: C = 100 pF, R = 1.5 k Ω .

5. Characteristics

Table 3.Electrical characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
f _i	input frequency			-	13.56	-	MHz
C _i	input capacitance	T _{amb} = 22 °C, [] f _i = 13.56 MHz; 2 V _{RMS}	1]	14.4	16.1	17.4	pF
EEPROM characteristics							
t _{cy(ER_W)}	erasure write cycle time			-	2.9	-	ms
t _{ret}	retention time	T _{amb} = 22 °C		10	-	-	year
N _{endu(ER_W)}	write or erase endurance	T _{amb} = 22 °C		100 000	-	-	cycle

[1] Measured with HP4285A, Precision LCR meter.

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6. Chip orientation and bond pad locations



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7. References

- [1] Data sheet General wafer specification for 8" wafers on UV-tape BU ID Doc. No.: 1005**3
- [2] Data sheet Standard card IC MF1ICS50 memory contents after test BU ID Doc. No.: 0061**
- [3] Data sheet Standard card IC MF1ICS50 functional specification BU ID Doc. No.: 0010**
- [4] Product qualification package Standard card IC MF1ICS5005 BU ID Doc. No. 0809***
- [5] Application note MIFARE, card IC coil design guide BU ID Doc. No. 0117**

8. Revision history

Table 4. Rev	vision history			
Document ID	Release date	Data sheet status	Change notice	Supersedes
179132	20100623	Product data sheet addendum	-	179131
Modifications:	Section 3.3: Correct	ed step size and scribe line width		
	 Figure 1: Added scr 	ibe line width dimension		
179131	20100210	Product data sheet addendum	-	179130
Modifications:	 Figure 1: chip drawi 	ng corrected		
	 Section 9 "Legal info 	ormation": updated		
179130	20100121	Product data sheet addendum	-	-

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^{3. ** ...} document version number

9. Legal information

9.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions"

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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